



BSI Standards Publication

**Surface chemical analysis — Depth profiling —
Methods for ion beam alignment and the
associated measurement of current or current
density for depth profiling in AES and XPS**

National foreword

This British Standard is the UK implementation of ISO 16531:2020. It supersedes BS ISO 16531:2013, which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee CII/60, Surface chemical analysis.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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